

Simulation of an effective 2-trap radiation damage model

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Simulations with an effective 2-trap radiation damage model have been performed. Adjustments of the EVL model and necessity of the adjustments are presented. In particular, the focus is on generated current after irradiation, depletion voltage and TCT simulation. Simulations are compared to IV, CV and TCT measurements done in the framework of the CMS HPK campaign.

Primary author: EBER, Robert (IEKP - KIT)

Presenter: EBER, Robert (IEKP - KIT)

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